

HM6604BWKR

Complementary Enhancement Mode Field Effect Transistor

General Description The HM6604BWKR uses advanced trench technology MOSFETs to provide excellent $R_{DS(ON)}$ and low gate charge. The complementary MOSFETs may be used to form a level shifted high side switch, an inverter, and for a host of other applications. Both devices are ESD protected. <i>HM6604BWKR are electrically identical.</i> -RoHS Compliant -HM6604BWKR is Halogen Free	Features n-channel $V_{DS} \text{ (V)} = 20V$ $I_D = 0.9A \text{ (} V_{GS}=4.5V \text{)}$ p-channel $-20V$ $-0.8A \text{ (} V_{GS}=-4.5V \text{)}$ $R_{DS(ON)}$ $< 270m\Omega \text{ (} V_{GS}=4.5V \text{)}$ $< 330m\Omega \text{ (} V_{GS}=2.5V \text{)}$ $< 450m\Omega \text{ (} V_{GS}=1.8V \text{)}$ $R_{DS(ON)}$ $< 480m\Omega \text{ (} V_{GS}=-4.5V \text{)}$ $< 950m\Omega \text{ (} V_{GS}=-2.5V \text{)}$ $< 2200m\Omega \text{ (} V_{GS}=-1.8V \text{)}$																																													
SC-70-6 (SOT-323) Top View S1 G1 D2 1 2 3 6 5 4 D1 G2 S2	D1 G S1 n-channel D2 G S2 p-channel																																													
Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted <table><tr><th>Parameter</th><th>Symbol</th><th>Max n-channel</th><th>Max p-channel</th><th>Units</th></tr><tr><td>Drain-Source Voltage</td><td>V_{DS}</td><td>20</td><td>-20</td><td>V</td></tr><tr><td>Gate-Source Voltage</td><td>V_{GS}</td><td>± 8</td><td>± 8</td><td>V</td></tr><tr><td>Continuous Drain Current^A</td><td>$T_A=25^{\circ}C$</td><td>0.9</td><td>-0.8</td><td rowspan="2">A</td></tr><tr><td></td><td>$T_A=70^{\circ}C$</td><td>0.7</td><td>-0.56</td></tr><tr><td>Pulsed Drain Current^B</td><td>I_{DM}</td><td>5</td><td>-2.4</td><td></td></tr><tr><td rowspan="2">Power Dissipation</td><td>$T_A=25^{\circ}C$</td><td>0.3</td><td>0.3</td><td rowspan="2">W</td></tr><tr><td>$T_A=70^{\circ}C$</td><td>0.19</td><td>0.19</td></tr><tr><td>Junction and Storage Temperature Range</td><td>T_J, T_{STG}</td><td>-55 to 150</td><td>-55 to 150</td><td>$^{\circ}C$</td></tr></table>					Parameter	Symbol	Max n-channel	Max p-channel	Units	Drain-Source Voltage	V_{DS}	20	-20	V	Gate-Source Voltage	V_{GS}	± 8	± 8	V	Continuous Drain Current ^A	$T_A=25^{\circ}C$	0.9	-0.8	A		$T_A=70^{\circ}C$	0.7	-0.56	Pulsed Drain Current ^B	I_{DM}	5	-2.4		Power Dissipation	$T_A=25^{\circ}C$	0.3	0.3	W	$T_A=70^{\circ}C$	0.19	0.19	Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	-55 to 150	$^{\circ}C$
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Thermal Characteristics: n-channel and p-channel						
Parameter		Symbol	Device	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$t \leq 10s$	$R_{\theta JA}$	n-ch	360	415	$^\circ C/W$
Maximum Junction-to-Ambient ^A	Steady-State		n-ch	400	460	$^\circ C/W$
Maximum Junction-to-Lead ^C	Steady-State	$R_{\theta JL}$	n-ch	300	350	$^\circ C/W$
Maximum Junction-to-Ambient ^A	$t \leq 10s$	$R_{\theta JA}$	p-ch	360	415	$^\circ C/W$
Maximum Junction-to-Ambient ^A	Steady-State		p-ch	400	460	$^\circ C/W$
Maximum Junction-to-Lead ^C	Steady-State	$R_{\theta JL}$	p-ch	300	350	$^\circ C/W$

N-Channel: Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$	20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=16\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^{\circ}\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 8\text{V}$			25	μA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	0.45		1.2	V
$I_{D(ON)}$	On state drain current	$V_{GS}=4.5\text{V}$, $V_{DS}=5\text{V}$	5			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}$, $I_D=0.9\text{A}$ $T_J=125^{\circ}\text{C}$		220	270	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}$, $I_D=0.75\text{A}$		260	330	$\text{m}\Omega$
		$V_{GS}=1.8\text{V}$, $I_D=0.7\text{A}$		330	450	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}$, $I_D=0.8\text{A}$		2.6		S
V_{SD}	Diode Forward Voltage	$I_S=0.5\text{A}$, $V_{GS}=0\text{V}$		0.69	1	V
I_S	Maximum Body-Diode Continuous Current				0.4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=10\text{V}$, $f=1\text{MHz}$		101	120	pF
C_{oss}	Output Capacitance			17		pF
C_{rss}	Reverse Transfer Capacitance			14		pF
R_g	Gate resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$		3	4	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=4.5\text{V}$, $V_{DS}=10\text{V}$, $I_D=0.8\text{A}$		1.57	1.9	nC
Q_{gs}	Gate Source Charge			0.13		nC
Q_{gd}	Gate Drain Charge			0.36		nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=5\text{V}$, $V_{DS}=10\text{V}$, $R_L=12.5\Omega$, $R_{GEN}=6\Omega$		3.2		ns
t_r	Turn-On Rise Time			4		ns
$t_{D(off)}$	Turn-Off DelayTime			15.5		ns
t_f	Turn-Off Fall Time			2.4		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=0.8\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		6.7	8.1	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=0.8\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		1.6		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using 80 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The SOA curve provides a single pulse rating.

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N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

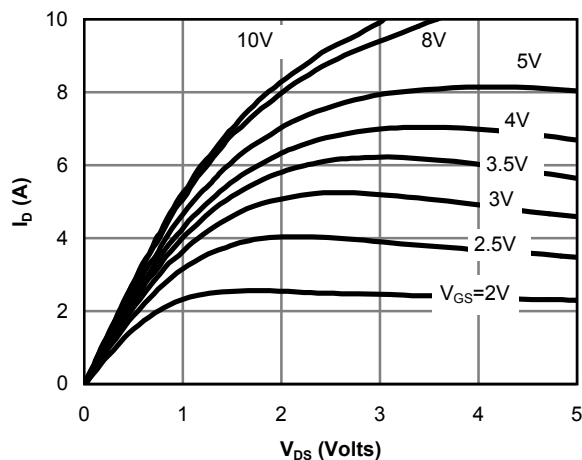


Fig 1: On-Region Characteristics

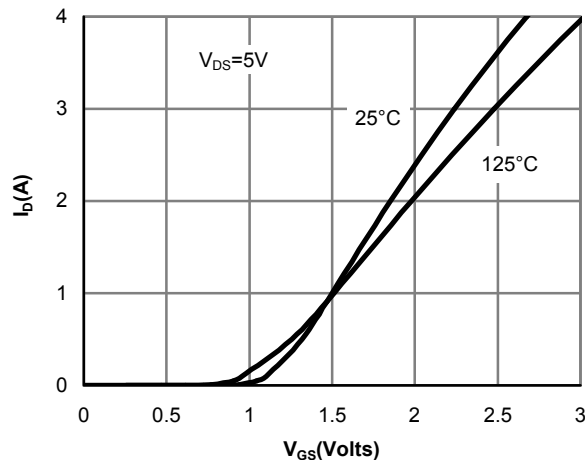


Figure 2: Transfer Characteristics

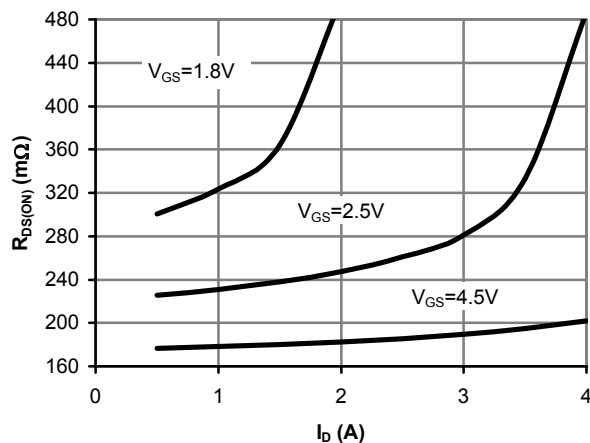


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

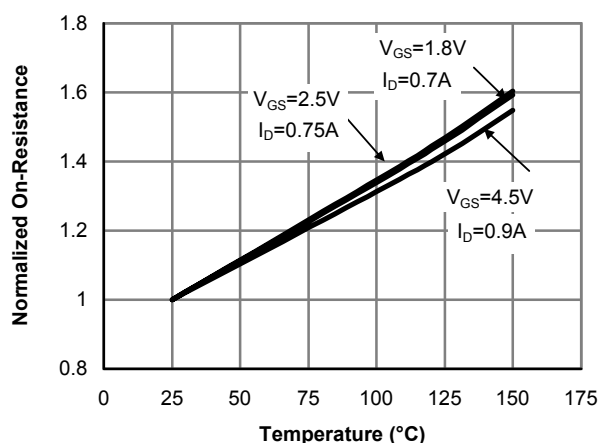


Figure 4: On-Resistance vs. Junction Temperature

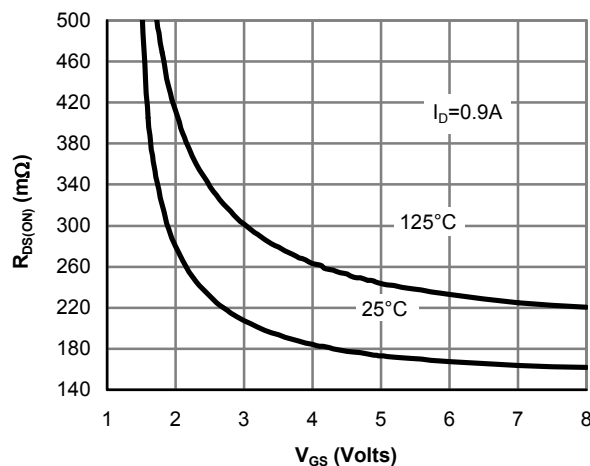


Figure 5: On-Resistance vs. Gate-Source Voltage

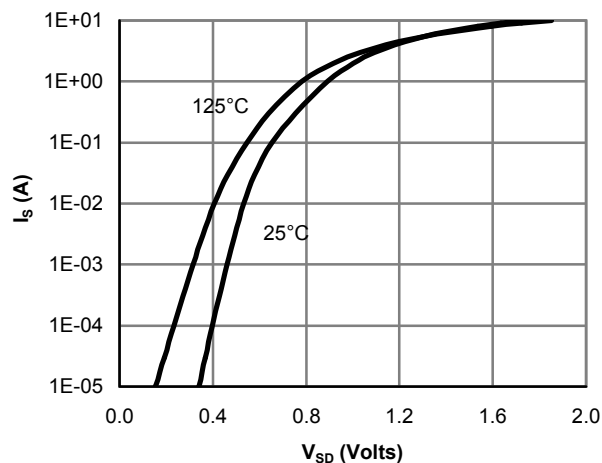


Figure 6: Body-Diode Characteristics

N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

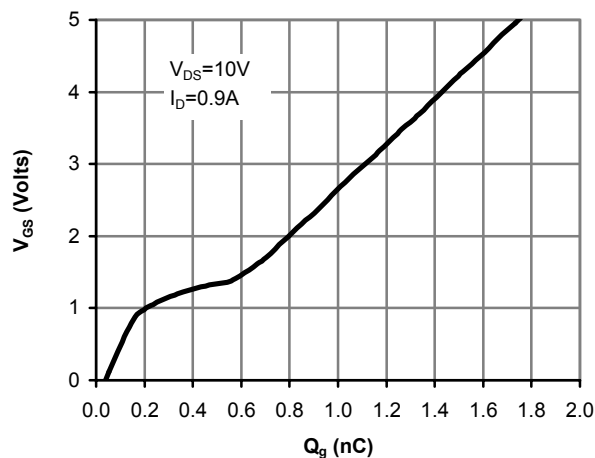


Figure 7: Gate-Charge Characteristics

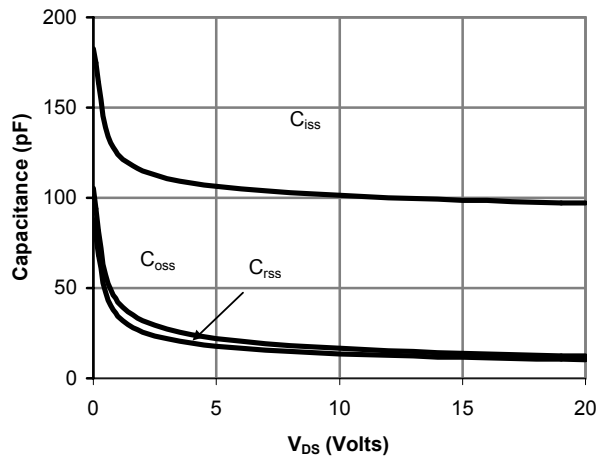


Figure 8: Capacitance Characteristics

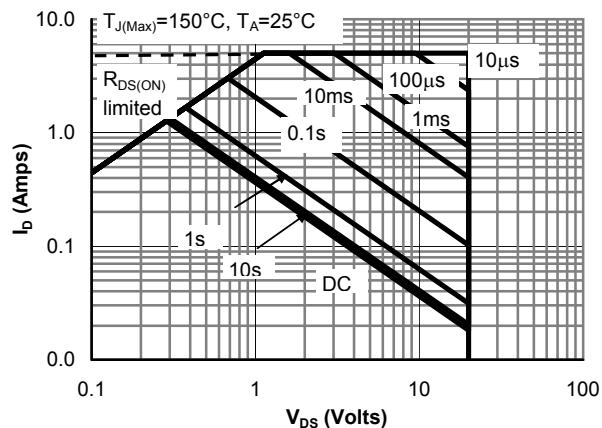


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

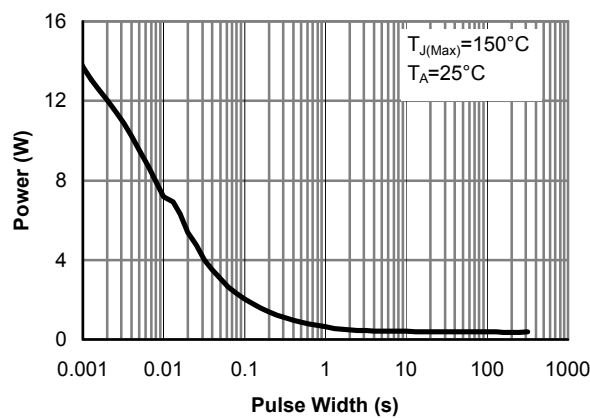


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

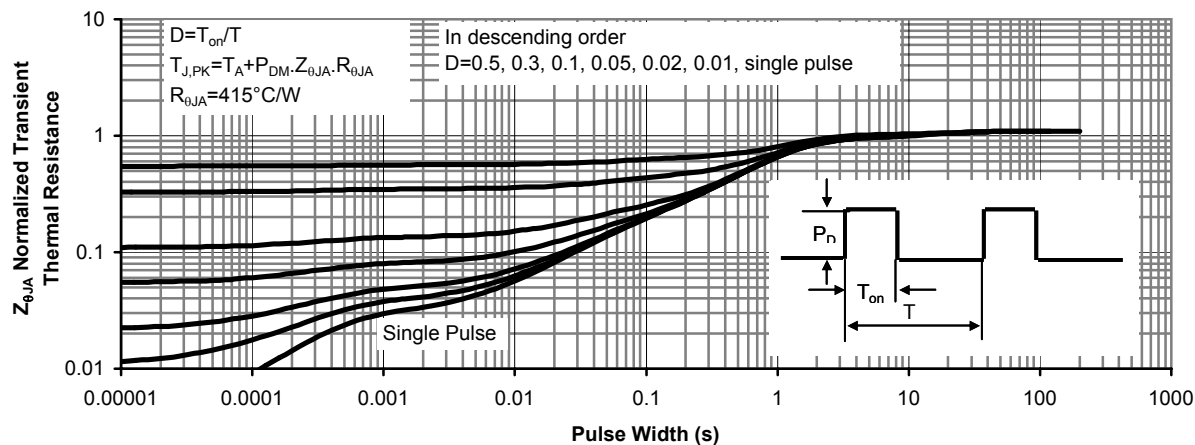


Figure 11: Normalized Maximum Transient Thermal Impedance

P-Channel Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-16\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^{\circ}\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 8\text{V}$			± 10	μA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$	-0.45		-1.2	V
$I_{D(ON)}$	On state drain current	$V_{GS}=-4.5\text{V}$, $V_{DS}=-5\text{V}$	-3			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}$, $I_D=-0.8\text{A}$ $T_J=125^{\circ}\text{C}$		350 440	480 670	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}$, $I_D=-0.5\text{A}$		550	950	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}$, $I_D=-0.4\text{A}$		780	2200	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-0.8\text{A}$		1.7		S
V_{SD}	Diode Forward Voltage	$I_S=-0.5\text{A}$, $V_{GS}=0\text{V}$		-0.86	-1	V
I_S	Maximum Body-Diode Continuous Current				-0.4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=-10\text{V}$, $f=1\text{MHz}$		114	140	pF
C_{oss}	Output Capacitance			17		pF
C_{rss}	Reverse Transfer Capacitance			14		pF
R_g	Gate resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$		12	17	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=-4.5\text{V}$, $V_{DS}=-10\text{V}$, $I_D=-0.8\text{A}$		1.44	1.8	nC
Q_{gs}	Gate Source Charge			0.14		nC
Q_{gd}	Gate Drain Charge			0.35		nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=-4.5\text{V}$, $V_{DS}=-10\text{V}$, $R_L=16.7\Omega$, $R_{GEN}=3\Omega$		6.5		ns
t_r	Turn-On Rise Time			6.5		ns
$t_{D(off)}$	Turn-Off DelayTime			18.2		ns
t_f	Turn-Off Fall Time			5.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-0.8\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		10	13	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-0.8\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		3		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $\leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

D: The static characteristics in Figures 1 to 6,12,14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The SOA curve provides a single pulse rating.

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P-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

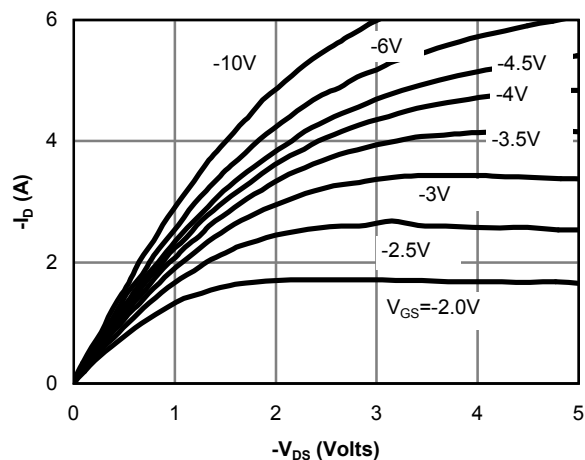


Fig 1: On-Region Characteristics

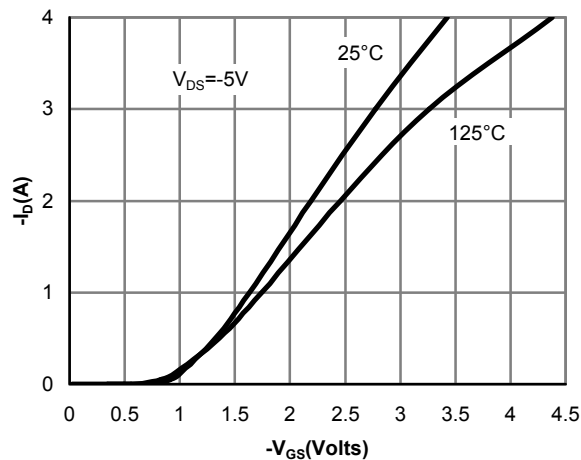


Figure 2: Transfer Characteristics

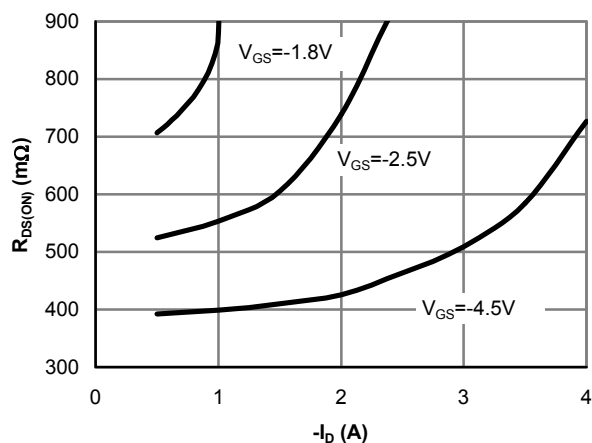


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

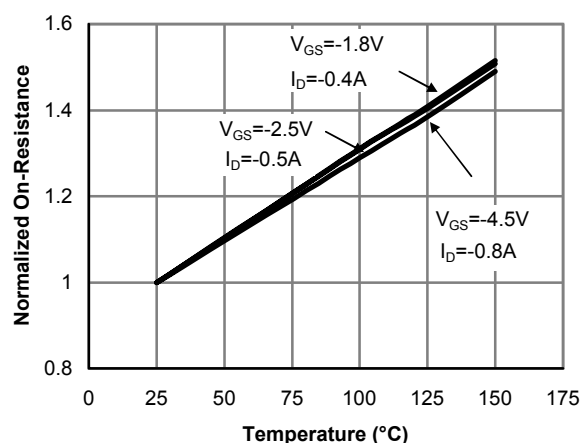


Figure 4: On-Resistance vs. Junction Temperature

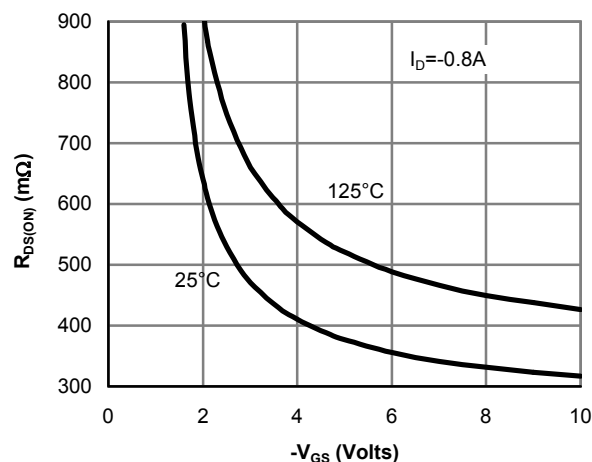


Figure 5: On-Resistance vs. Gate-Source Voltage

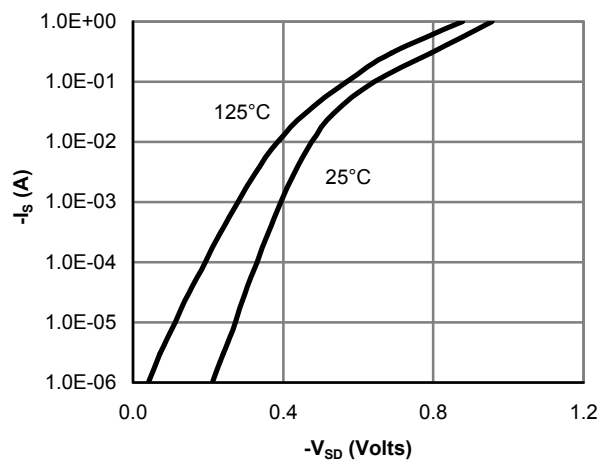
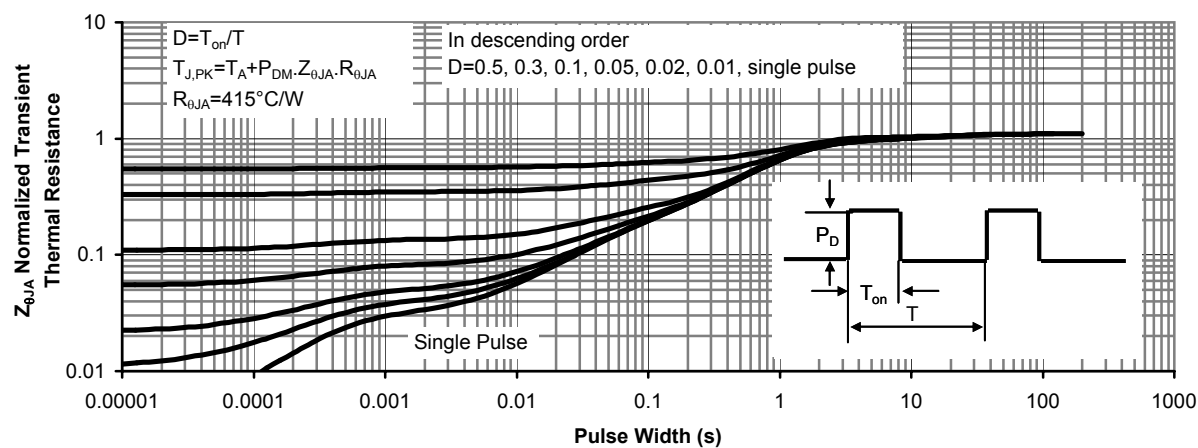
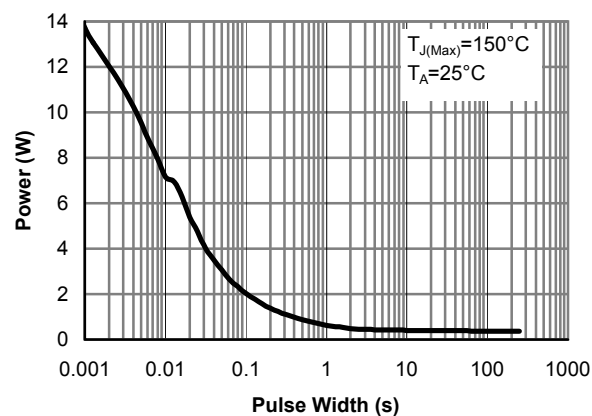
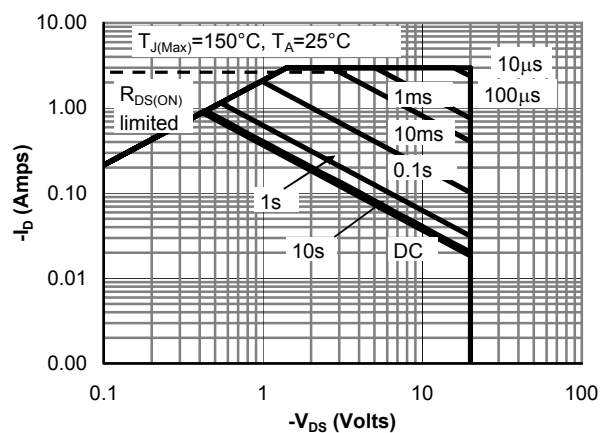
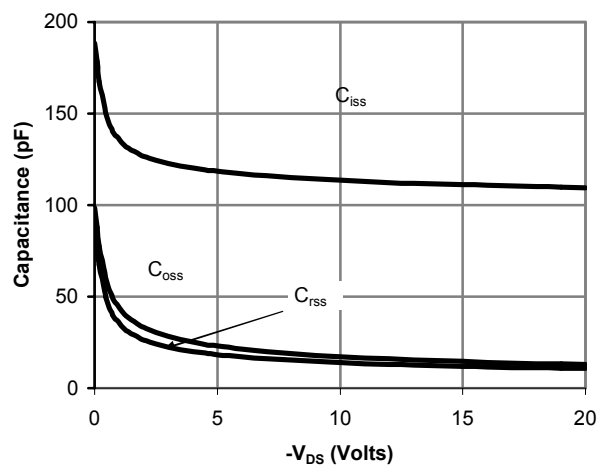
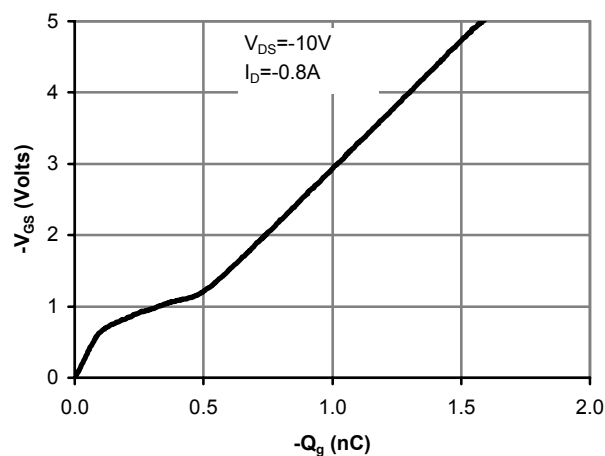


Figure 6: Body-Diode Characteristics

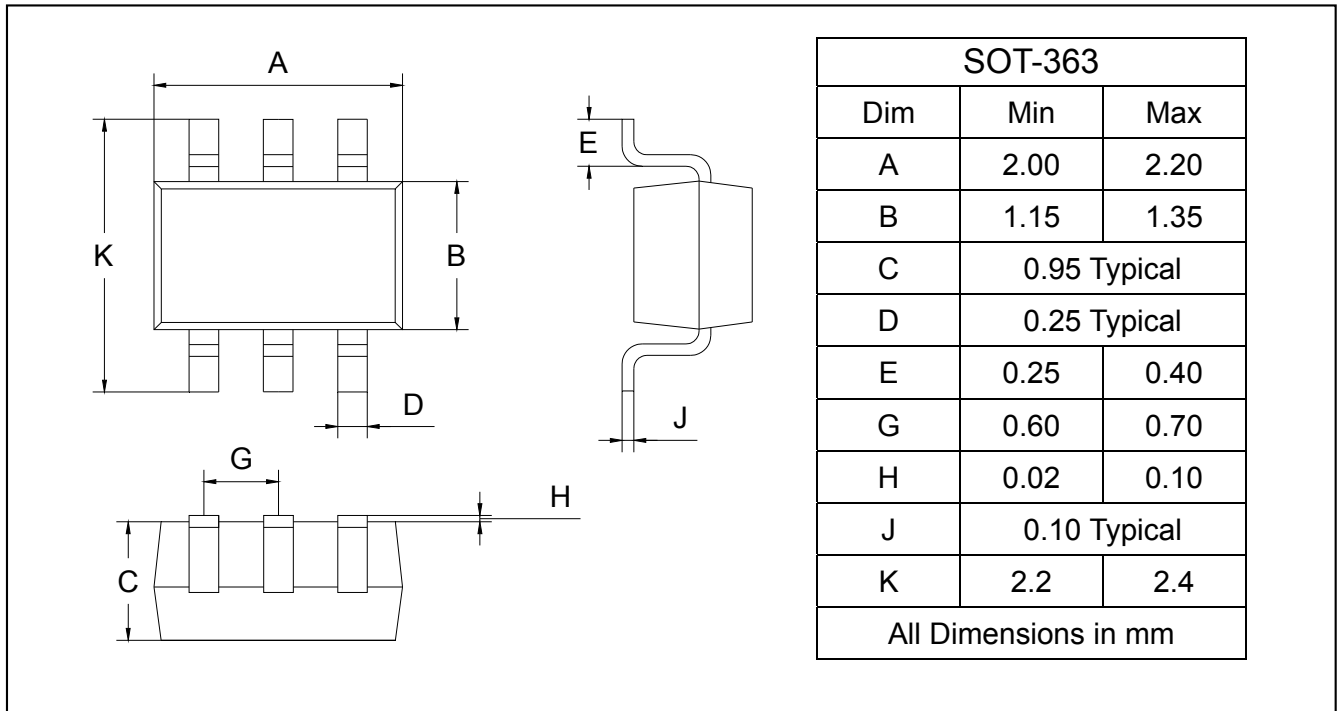
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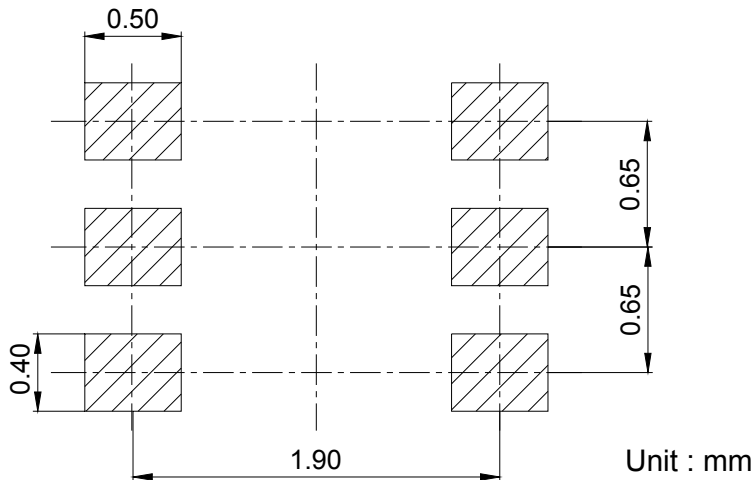
PACKAGE OUTLINE

Plastic surface mounted package

SOT-363



SOLDERING FOOTPRINT



PACKAGE INFORMATION

Device	Package	Shipping
HM6604BWKR	SOT-363	3000/Tape&Reel